

### SANYO Semiconductors DATA SHEET

## 2SK3099LS—General-Purpose Switching Device Applications

#### **Features**

- · Low ON-resistance.
- · Low Qg.
- · Ultrahigh-Speed Switching Applications.
- · Avalanche resistance guarantee.

#### **Specifications**

#### Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		400	V
Gate-to-Source Voltage	VGSS		±30	V
Drain Current (DC)	ID		9	Α
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	36	Α
Allowable Power Dissipation	D-		2.0	W
	PD	Tc=25°C	35	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C
Avalanche Enargy (Single Pulse) *1	EAS		92.6	mJ
Avalanche Current *2	IAV		9	Α

<sup>\*1</sup> VDD=50V, L=2mH, IAV=9A

#### Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=1mA, VGS=0V	400			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =320V, V <sub>GS</sub> =0V			1.0	mA
Gate-to-Source Leakage Current	IGSS	VGS= ±30V, VDS=0V			±100	nA
Cutoff Voltage	VGS(off)	V <sub>DS</sub> =10V, I <sub>D</sub> =1mA	3.0		4.0	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> =10V, I <sub>D</sub> =6A	2.9	5.8		S
Static Drain-to-Source On-State Resistance	RDS(on)	ID=6A, VGS=15V		0.43	0.55	Ω

Marking: K3099 Continued on next page.

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<sup>\*2</sup> L≤2mH, single pulse

#### 2SK3099LS

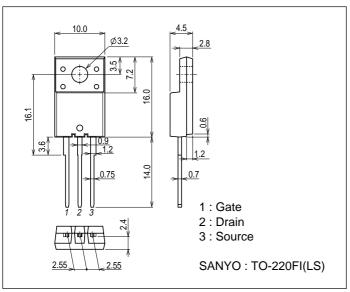
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Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Input Capacitance	Ciss	V <sub>DS</sub> =20V, f=1MHz		1150		pF
Output Capacitance	Coss	V <sub>DS</sub> =20V, f=1MHz		350		pF
Reverse Transfer Capacitance	Crss	V <sub>DS</sub> =20V, f=1MHz		150		pF
Turn-ON Delay Time	t <sub>d</sub> (on)	See specified Test Circuit.		20		ns
Rise Time	t <sub>r</sub>	See specified Test Circuit.		35		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See specified Test Circuit.		85		ns
Fall Time	tf	See specified Test Circuit.		45		ns
Total Gate Charge	Qg	V <sub>DS</sub> =200V, V <sub>GS</sub> =10V, I <sub>D</sub> =9A		40		nC
Diode Forward Voltage	VSD	IS=9A, VGS=0V	·	0.95	1.2	V

Note: Be careful in handling the 2SK3099LS because it has no protection diode between gate and source.

#### **Package Dimensions**

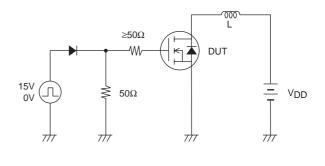
unit : mm (typ) 7509-002



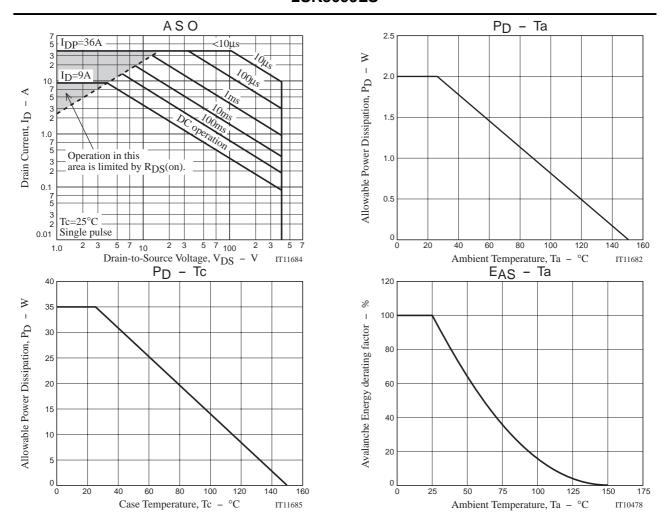
#### **Switching Time Test Circuit**

# $\begin{array}{c|c} & V_{DD}\text{=}200V \\ \hline & V_{GS}\text{=}15V \\ \hline & PW\text{=}10\mu\text{s} \\ D.C.\text{\le}0.5\% \\ \hline & R_{L}\text{=}33.3\Omega \\ \hline & V_{OUT} \\ \hline & PRG \\ \hline & S \\ \end{array}$

#### **Avalanche Resistance Test Circuit**



#### 2SK3099LS



Note on usage: Since the 2SK3099LS is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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